



Next Generation X-Ray Optics (NGXO)

Reflective Coating for Lightweight Segmented X-ray Optics

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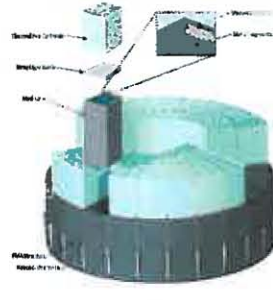
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X-Ray Optics for Astronomy

- Next generation x-ray optics for astronomy will require segmented, lightweight optics
- Compact, thin shell $\Rightarrow$ low cost ($\sim$ Suzuki)
- High angular resolution is the frontier ($\sim$ arc-second)



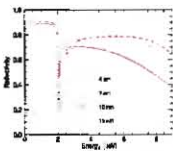
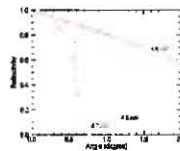
Segmented Thin-Shell Mirror



Modular X-ray Telescope

Mirror = Substrate + Reflective Coating

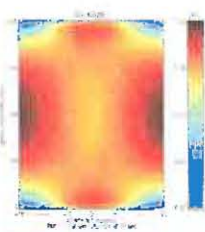
- Precise, thin, large, glass substrates (a few arc-seconds) are now developed and resolution is improving
- Low stress, high-Z coating is needed for x-ray reflection for $E < 10$ keV. Multi-layer for harder x-ray.
- Requires about 20 nm of single layer film of high-Z metal (e.g., Ir, Pt)



Coating and Angular Resolution

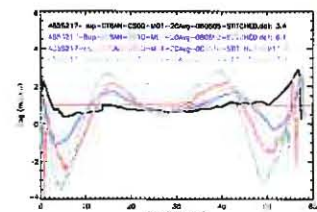
- Does coating matter structurally? For arc-second resolution optics, yes.
- Coating stress $\sim$ GPa (20 nm film) is high enough to distort thin shell mirror
- Example: Sag of $\sim 1 \mu\text{m}$ from 3 GPa, 20 nm film on 0.4 mm glass substrate of 200 mm long

$$K = \frac{(1-\nu)\sigma t}{Et^2}$$



Coating with Magnetron-Sputtering

- Film stresses are high:
 - Ir: ~ 4 GPa (compressive)
 - Cr: ~ 2 GPa (Tensile)
- Successively depositing thicker films on mirrors progressively worsens its axial curvature



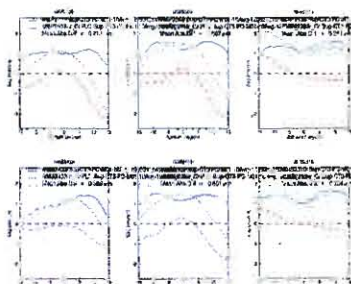
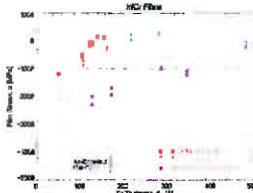
Two approaches to eliminate film stress-induced distortion:

1. Low stress Ir/Cr bi-layer
2. Conformal front and back side deposition

Run	Sample/Model	Thickness (nm)	Stress (GPa)
1	Crude	20-40	$< 0.5 \pm 0.2$
2	Bi-layer	15-30	-0.8 ± 0.14
3	Thin	15-30	-0.5 ± 0.05
4	Thin	15-30	1.0 ± 0.1

Low stress Ir/Cr bi-layer deposition

- Take advantage of compressive Ir and tensile Cr
- Combined Ir/Cr bi-layer deposition will produce zero stress film
- Calibration of Cr film with variable thickness reduces the effective stress of Ir/Cr film to within ± 0.1 GPa



+221 MPa

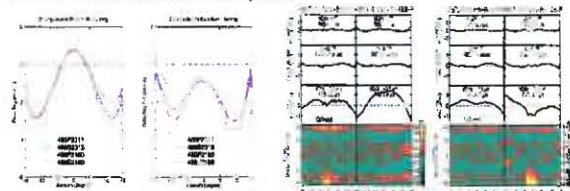
-426 MPa

-887 MPa

Sag variation of Mirror, as functions of Azimuths

Conformal Front-side and Backside deposition

- Coating-induced distortion of mirror may be balanced by coating both front side and the back side of the mirror
- Requires matching (preferably uniform) thickness and stress distribution over mirror's surfaces
- Back side coated mirrors are also thermally useful



Front and Back side Deposition with Magnetron-sputtering

- Front-side deposition produces sag variation as expected
- Back-side deposition produces consistent, similar sag change
- But magnitudes do not match exactly, especially at middle azimuths
- Geometry difference of mirrors mounted in the coating chamber

Conformal Front and Back Coating with Atomic Layer Deposition (ALD)

- The case for ALD
 - Conformal coating on all surfaces
 - Uniform coat
 - Potentially lower stress
 - Dense and smooth films
- Preliminary results are encouraging
- Currently engaging local facilities and thin film equipment providers for further development

Further Information

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 Mirror Metrology: Timo.Saha@nasa.gov
 Alignment and Bonding: Michael.Biskach@nasa.gov
 FMA/Modules: Ryan.S.McClelland@nasa.gov

References

- [1] William W. Zhang, et al., "Next generation x-ray optics: high-resolution, light-weight, and low-cost", Proc. SPIE 8443-28, (2012).
- [2] Ryan S. McClelland, et al., "Design and analysis of modules for segmented glass x-ray optics", Proc. SPIE 8443-144, (2012).
- [3] Michael Biskach, et al., "Precise alignment and permanent mounting of thin and lightweight x-ray segments", Proc. SPIE 8443-145, (2012).

